



PATENT

11/26/2007 2133
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Rajski et al.**Application No.** 09/620,021**Filed:** July 20, 2000**Confirmation No.** 3823**For:** CONTINUOUS APPLICATION AND
DECOMPRESSION OF TEST PATTERN
TO A CIRCUIT-UNDER-TEST**Examiner:** Phung M. Chung**Art Unit:** 2133**Attorney Reference No.** 1011-54375-01**CERTIFICATE OF MAILING**

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37 C.F.R. § 1.97(c)**

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Applicants will provide copies of such patents or applications upon request.

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Submitted herewith is a check for \$180.00 as required by 37 C.F.R. § 1.17(p) for filing this IDS in compliance with 1.97(c).

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Respectfully submitted,

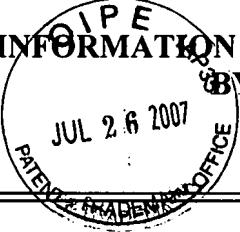
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Docketing

 <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p>	Attorney Docket Number	1011-54375-01
	Application Number	09/620,021
	Filing Date	July 20, 2000
	First Named Inventor	Rajski
	Art Unit	2133
	Examiner Name	Phung M. Chung

U.S. PATENT DOCUMENTS

Copies of U.S. Patent documents do not need to be provided, unless requested by the Patent and Trademark Office. For patents, provide the patent number and the issue date. For published U.S. applications, provide the publication number and the publication date. For unpublished pending patent applications, provide the application number and the filing date.

Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee

FOREIGN PATENT DOCUMENTS

Examiner's Initials*	Cite No. (optional)	Country	Number	Publication Date	Name of Applicant or Patentee

Examiner's Initials*	Cite No. (optional)	OTHER DOCUMENTS
		Chakrabarty et al., "Optimal Space Compaction of Test Responses," <i>Proc. ITC</i> , pp. 834-843 (1995).
		Chakrabarty et al., "Test Response Compaction Using Multiplexed Parity Trees," <i>IEEE Trans. CAD</i> , Vol. CAD-15, No. 11, pp. 1399-1408 (1996).
		Ivanov et al., "Programmable BIST Space Compactors," <i>IEEE Trans. Computers</i> , Vol. 45, No. 12, pp. 1393-1404 (1996).
		Pouya et al., "Synthesis of Zero-Aliasing Elementary-Tree Space Compactors," <i>Proc. VLSI Test Symp.</i> , pp. 70-77 (1998).
		Reddy et al., "A Data Compression Technique for Built-In Self-Test," <i>IEEE Trans. Computers</i> , Vol. 37, No. 9, pp. 1151-1156 (1988).
		Wunderlich, "Multiple Distributions for Biased Random Test Patterns," <i>Proc. ITC</i> , pp. 236-244 (1988).
		Yamaguchi et al., "An Efficient Method for Compressing Test Data," <i>Proc. ITC</i> , pp. 79-88 (1997).

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* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.